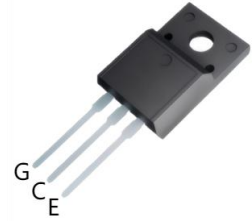
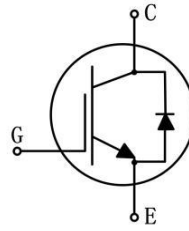


Trench Field-stop IGBT Discrete

Parameter	Value	Unit
V_{CE}	650	V
I_C	20	A
$V_{CE(sat)}$	1.75	V



TO-220F

Features

- Positive temperature coefficient.
- Fast Switching
- LOW $V_{CE(sat)}$
- Reliable and Rugged

Applications

- Motor drives
- Air Condition
- Inverters

Maximum Ratings

Parameter	Symbol	Value	Unit
		220F	
Collector-emitter voltage	V_{CES}	650	V
Gate-emitter voltage	V_{GES}	± 30	V
Continuous collector current($T_C=25^\circ C$)	I_C	40	A
Continuous collector current($T_C=100^\circ C$)		20	A
Pulsed collector current,tp limited by T_{vjmax}	I_{CM}	60	A
Diode continuous forward current($T_C=25^\circ C$)	I_F	40	A
Diode continuous forward current($T_C=100^\circ C$)		20	A
Diode maximum current,tp limited by T_{vjmax}	I_{FM}	60	A
Short Circuit withstand Time	t_{sc}	10	μs
Power dissipation($T_C=25^\circ C$)	P_{tot}	176	W
Operating junction temperature range	T_{vj}	-55 to+175	$^\circ C$
Storage temperature range	T_{Stg}	-55 to+175	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value		Unit
		Typ	Max.	
Thermal resistance,junction to case for IGBT	$R_{th(j-c)}$	-	0.85	$^\circ C/W$
Thermal resistance,junction to case for Diode	$R_{th(j-c)}$	-	0.98	$^\circ C/W$
Thermal resistance,junction to ambient	$R_{th(j-a)}$	-	40	$^\circ C/W$

Electrical Characteristics of IGBT ($T_{vj}=25^{\circ}\text{C}$ unless otherwise noted)
Static characteristics

Parameter	Symbol	Test condition	Value			Unit
			Min.	Typ.	Max.	
Collector-emitter breakdown voltage	$B_{V_{CES}}$	$V_{GE}=0V, I_C=250\mu A$	650	-	-	V
Collector-emitter leakage current	I_{CES}	$V_{CE}=650V, V_{GE}=0V$	-	-	10	μA
Gate leakage current, forward	I_{GES}	$V_{GE}=\pm 20V, V_{CE}=0V$	-	-	± 200	nA
Gate-emitter threshold voltage	$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C=1mA$	4.3	5.3	6.3	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=20A$	-	1.75	2.05	V
		$V_{GE}=15V, I_C=20A, T_{vj}=175^{\circ}\text{C}$	-	1.98	-	V

Dynamic Characteristics

Parameter	Symbol	Test condition	Value			Unit
			Min.	Typ.	Max.	
Input capacitance	C_{ies}	$V_{CE}=25V$	-	780	-	pF
Output capacitance	C_{oes}	$V_{GE}=0V$	-	46	-	pF
Reverse transfer capacitance	C_{res}	$f=1MHz$	-	22	-	pF
Total gate charge	Q_g	$V_{CC}=520V$	-	45	-	nC
Gate-Emitter Charge	Q_{ge}	$V_{GE}=15V$	-	9	-	nC
Gate-Collector Charge	Q_{gc}	$I_C=20A$	-	22	-	nC

Switching Characteristics

Parameter	Symbol	Test condition	Values			Unit	
			Min.	Typ.	Max.		
Turn-on delay time	$t_{d(on)}$	$V_{CC}=400V$ $V_{GE}=15V$ $I_C=20A$ $R_G=5\Omega$ Inductive load	-	12	-	ns	
Rise time	t_r		-	24	-	ns	
Turn-off delay time	$t_{d(off)}$		-	40	-	ns	
Fall time	t_f		-	68	-	ns	
Turn-on energy	E_{on}		-	0.26	-	mJ	
Turn-off energy	E_{off}		-	0.39	-	mJ	
Total switching energy	E_{ts}		-	0.65	-	mJ	
Turn-on delay time	$t_{d(on)}$		$V_{CC}=400V$ $V_{GE}=15V$ $I_C=20A$ $R_G=5\Omega$ Inductive load $T_{vj}=175^{\circ}\text{C}$	-	14	-	ns
Rise time	t_r			-	32	-	ns
Turn-off delay time	$t_{d(off)}$			-	81	-	ns
Fall time	t_f			-	60	-	ns
Turn-on energy	E_{on}			-	0.4	-	mJ
Turn-off energy	E_{off}	-		0.57	-	mJ	
Total switching energy	E_{ts}	-		0.97	-	mJ	

Diode Characteristics

Parameter	Symbol	Test condition	Values			Unit
			Min.	Typ.	Max.	
Diode forward voltage	V_F	$I_F=20A$	-	1.46	1.76	V
		$I_F=20A \quad T_{vj}=175^\circ C$	-	1.3	-	V
Diode reverse recovery time	t_{rr}	$V_R=400V$	-	47	-	ns
Diode peak reverse recovery current	I_{rrm}	$I_F=20A$	-	4.8	-	A
Diode reverse recovery charge	Q_{rr}	$diF/dt=-200A/\mu s$	-	67	-	nC
Diode reverse recovery time	t_{rr}	$V_R=400V$	-	62	-	ns
Diode peak reverse recovery current	I_{rrm}	$I_F=20A$	-	6.3	-	A
Diode reverse recovery charge	Q_{rr}	$diF/dt=-200A/\mu s \quad T_{vj}=175^\circ C$	-	102	-	nC

Typical Characteristics

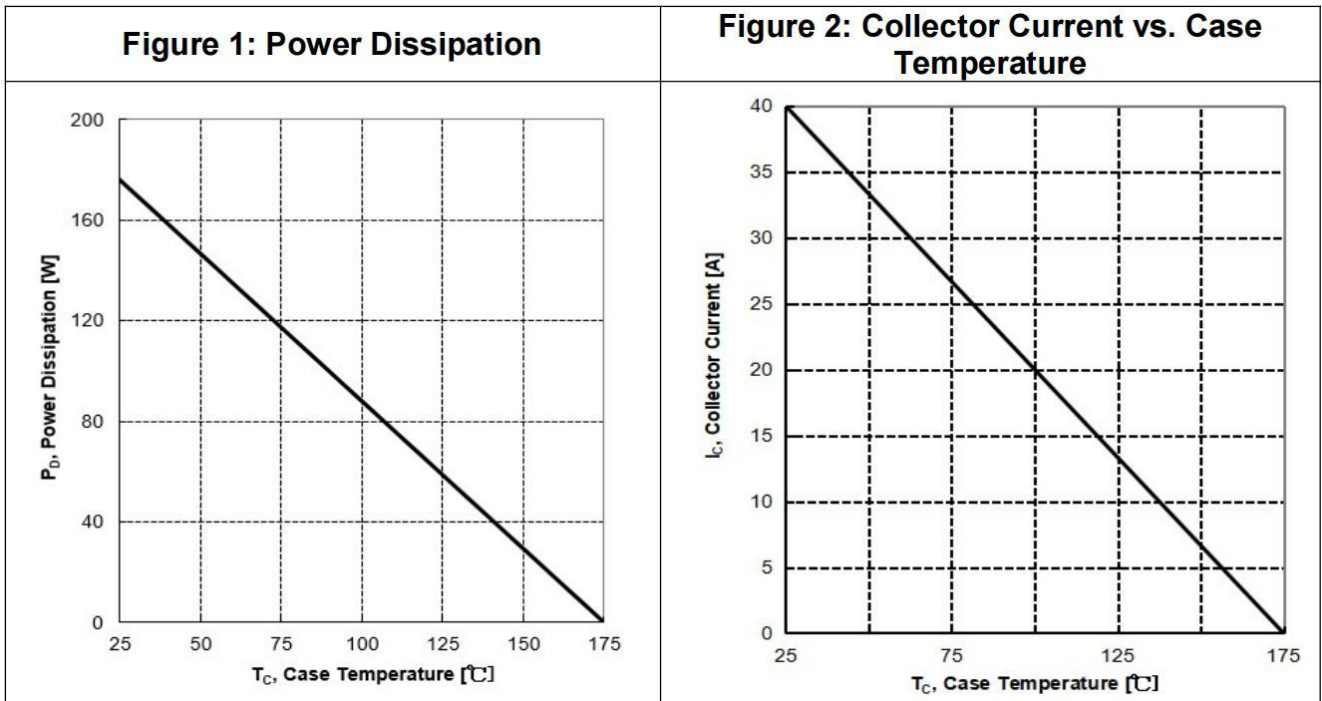


Figure 3: Safe Operation Area

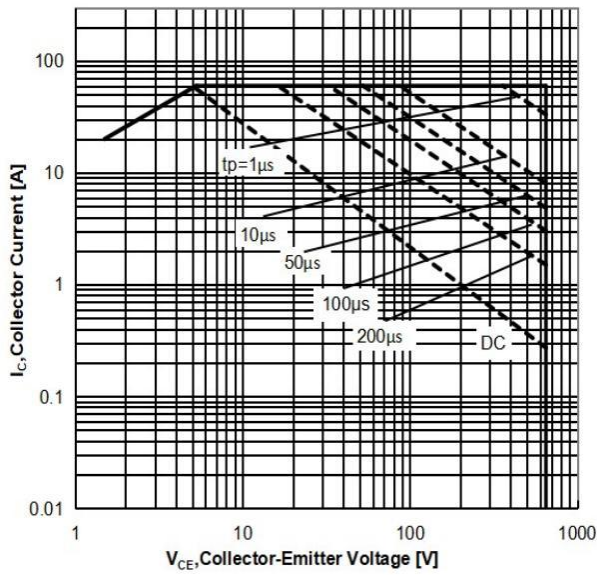


Figure 4: Typical Transfer Characteristics

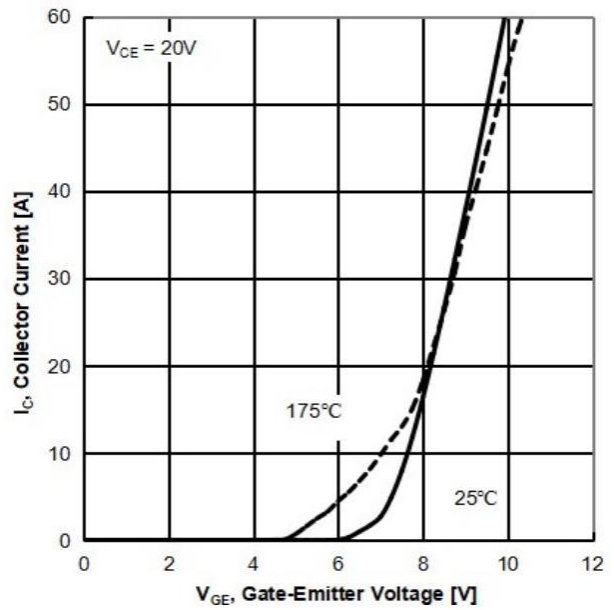


Figure 5: Typical Output Characteristics

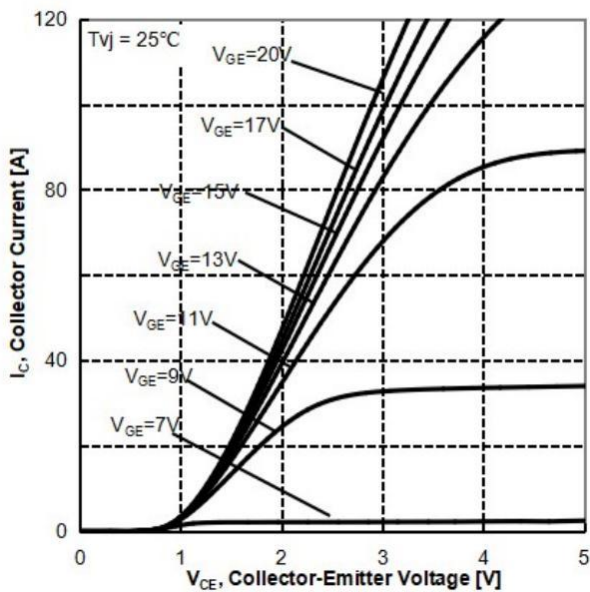


Figure 6: Typical Output Characteristics

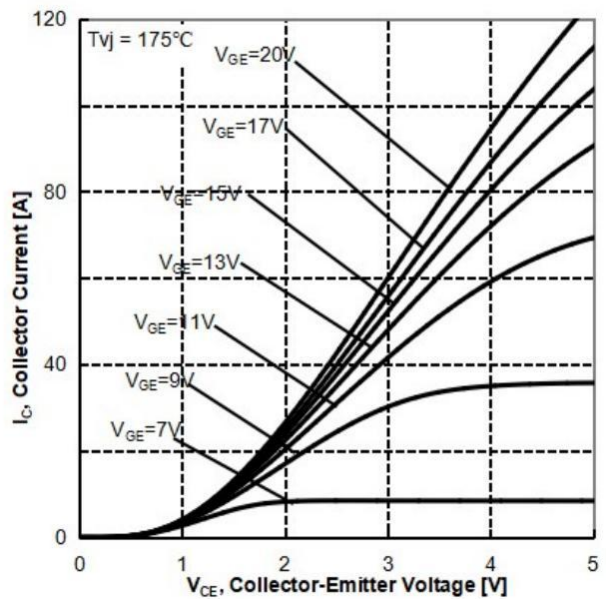


Figure 7: Typical Collector-Emitter Saturation Voltage vs. Junction Temperature

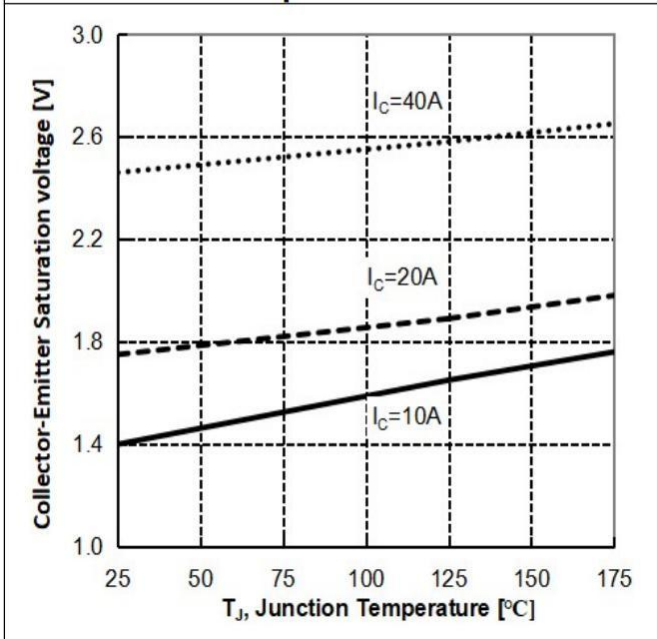


Figure 8: Typical Gate-Emitter Threshold Voltage vs. Junction Temperature

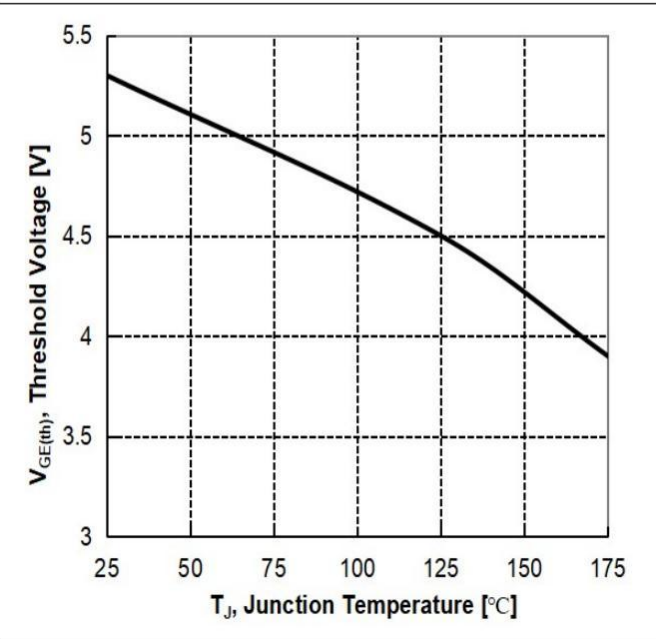


Figure 9: Typical Switching Times vs. Gate Resistor ($T_J=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $I_C=20A$)

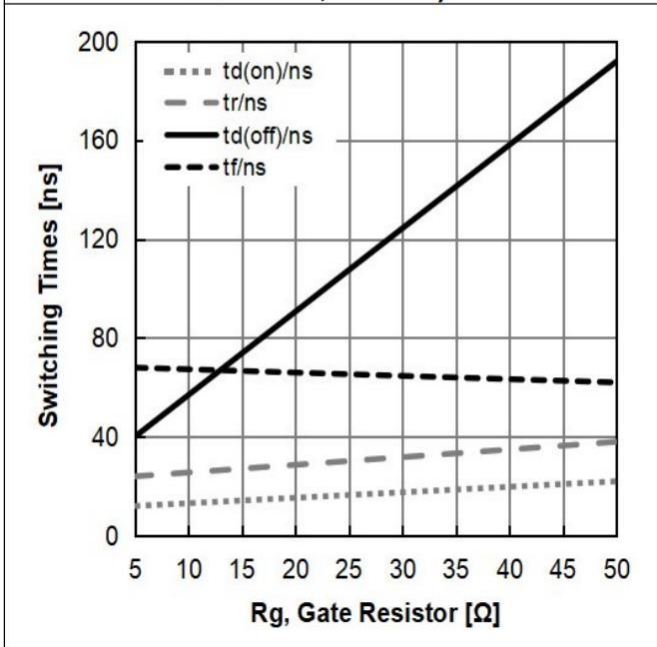


Figure 10: Typical Switching Energy vs. Gate Resistor ($T_J=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $I_C=20A$)

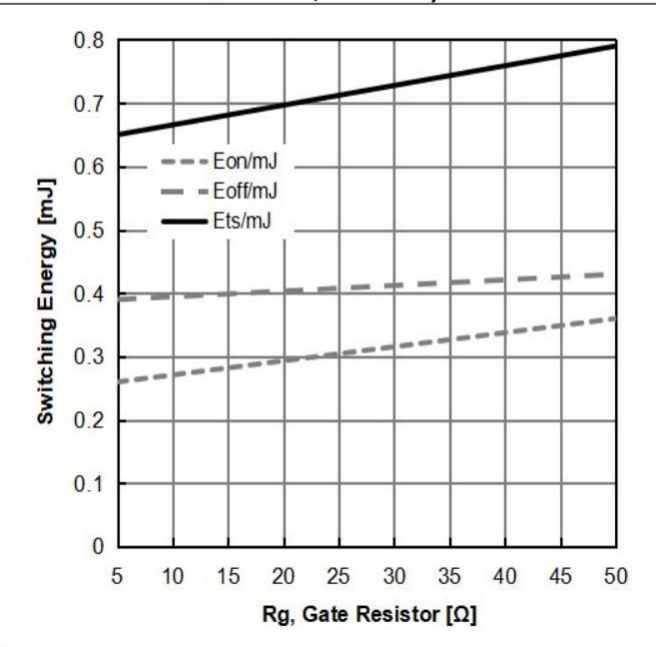


Figure 11: Typical Switching Times vs. Junction Temperature ($V_{CE}=400V$, $V_{GE}=15V$, $I_C=20A$, $R_g=5\Omega$)

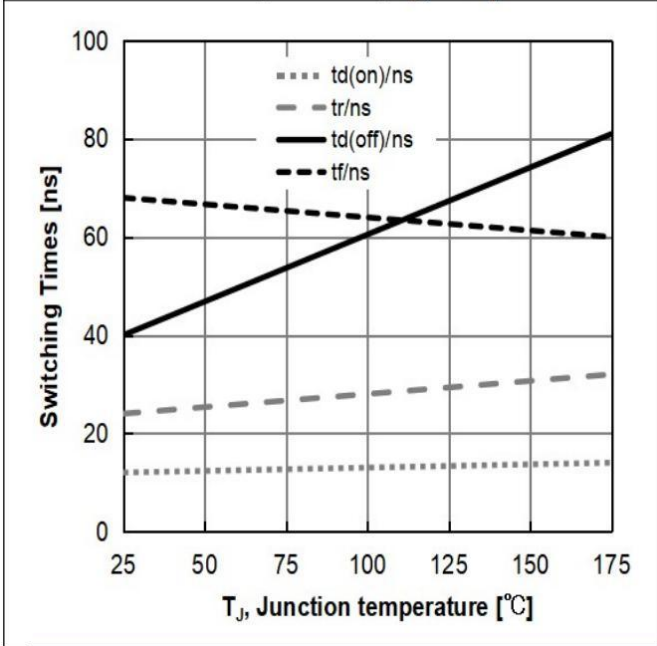


Figure 12: Typical Switching Energy vs. Junction Temperature ($V_{CE}=400V$, $V_{GE}=15V$, $I_C=20A$, $R_g=5\Omega$)

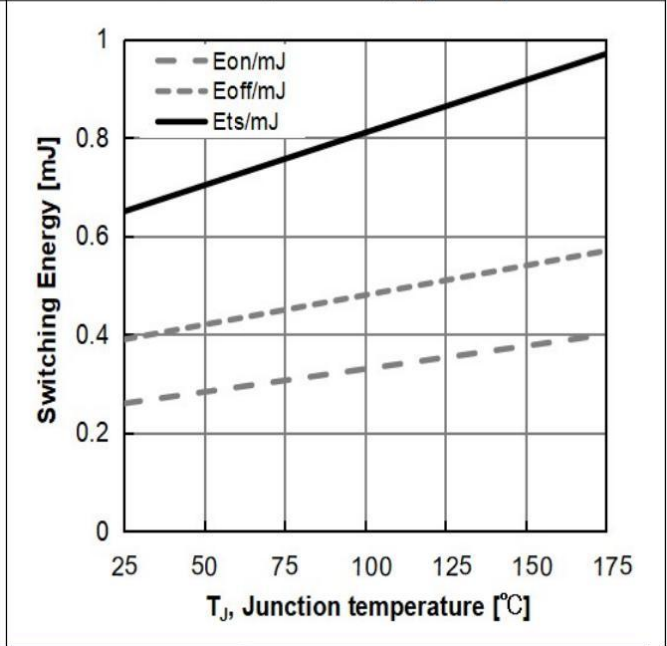


Figure 13: Typical Switching Times vs. Collector Current ($T_J=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $R_g=5\Omega$)

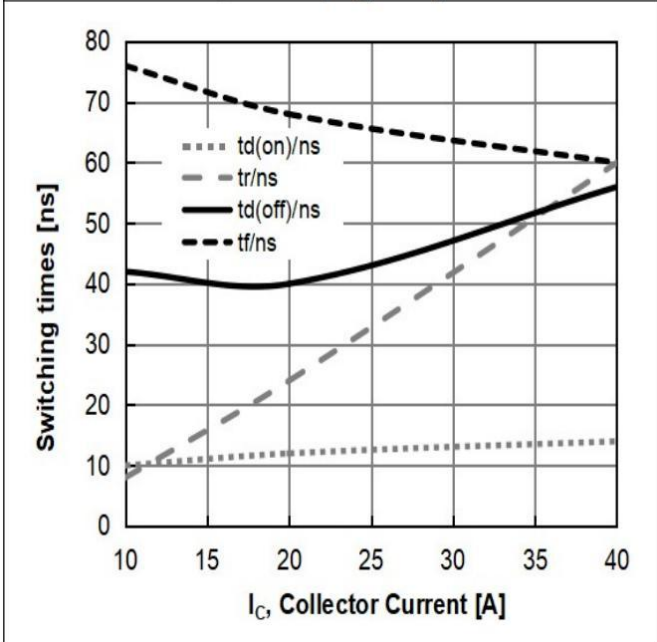


Figure 14: Typical Switching Energy vs. Collector Current ($T_J=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $R_g=5\Omega$)

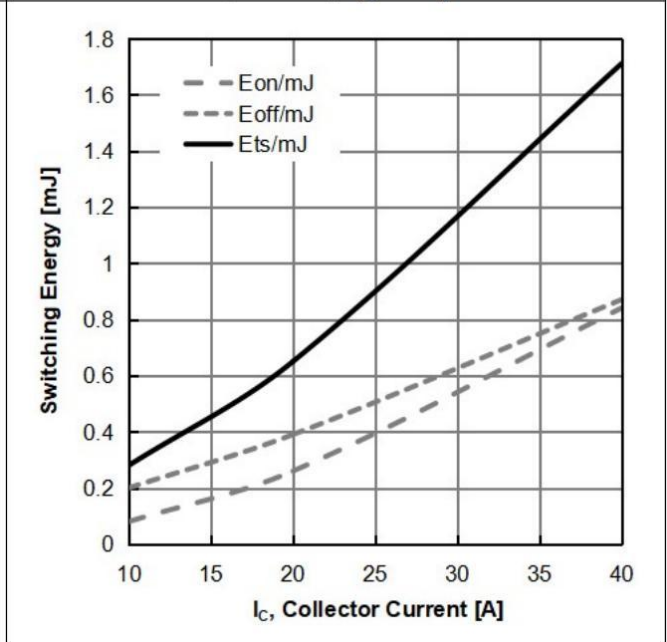


Figure 15: Typical Switching Times vs. VCE ($T_J=25^\circ\text{C}$, $V_{GE}=15\text{V}$, $I_C=20\text{A}$, $R_g=5\Omega$)

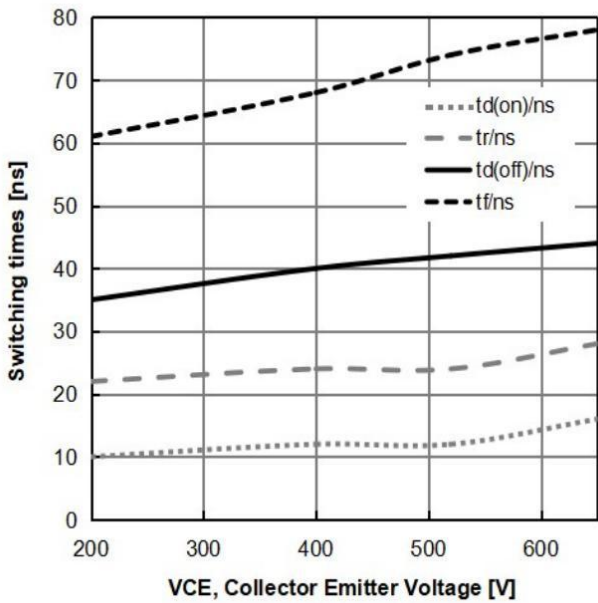


Figure 16: Typical Switching Energy vs. VCE ($T_J=25^\circ\text{C}$, $V_{GE}=15\text{V}$, $I_C=20\text{A}$, $R_g=5\Omega$)

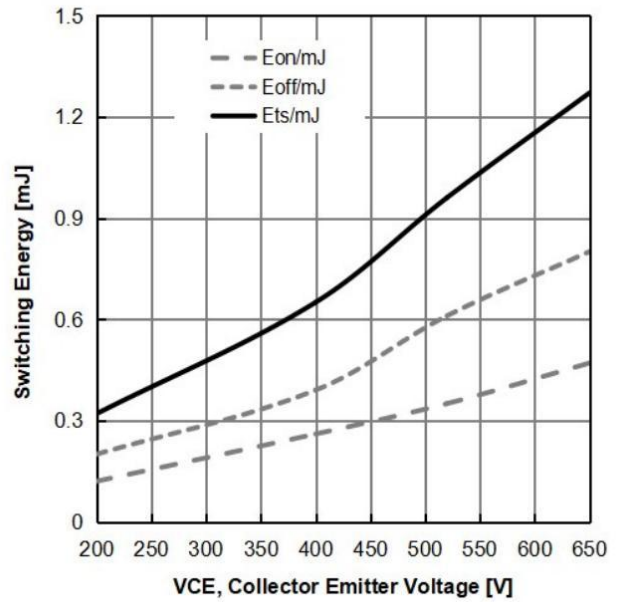


Figure 17: Typical Capacitance vs. Collector- Emitter Voltage

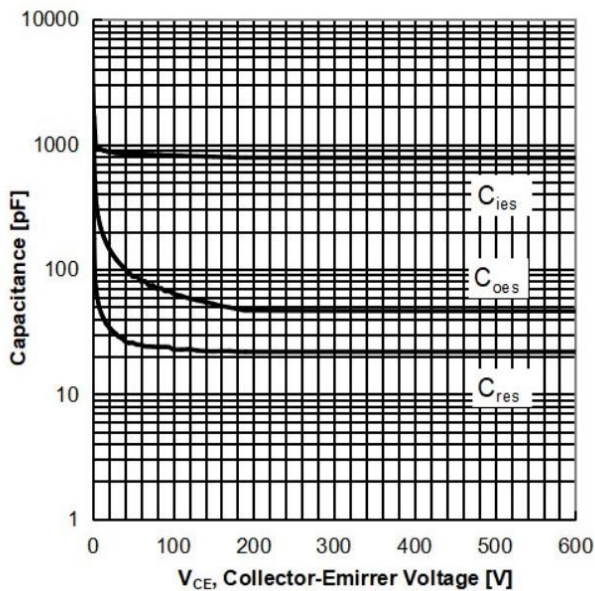


Figure 18: Typical Gate Charge

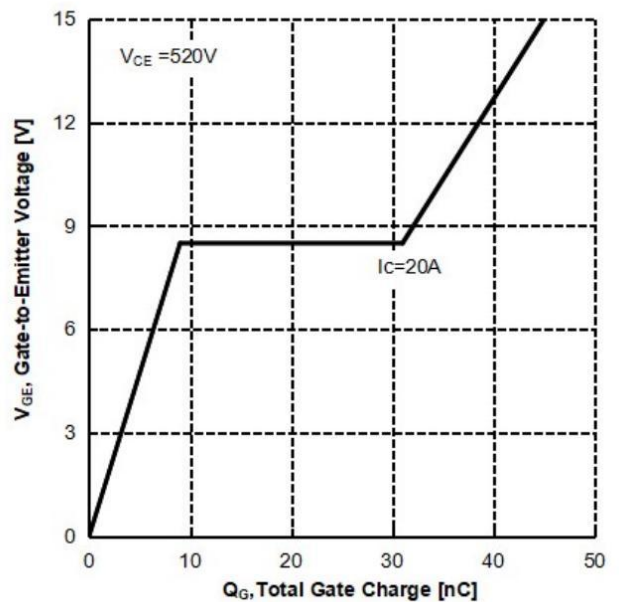


Figure 19: IGBT Transient Thermal Impedance vs. Pulse Width

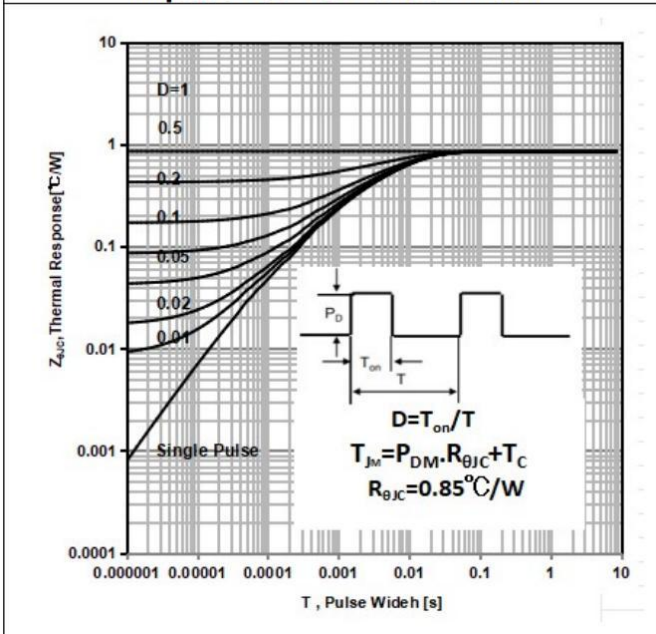


Figure 20: Diode Transient Thermal Impedance vs. Pulse Width

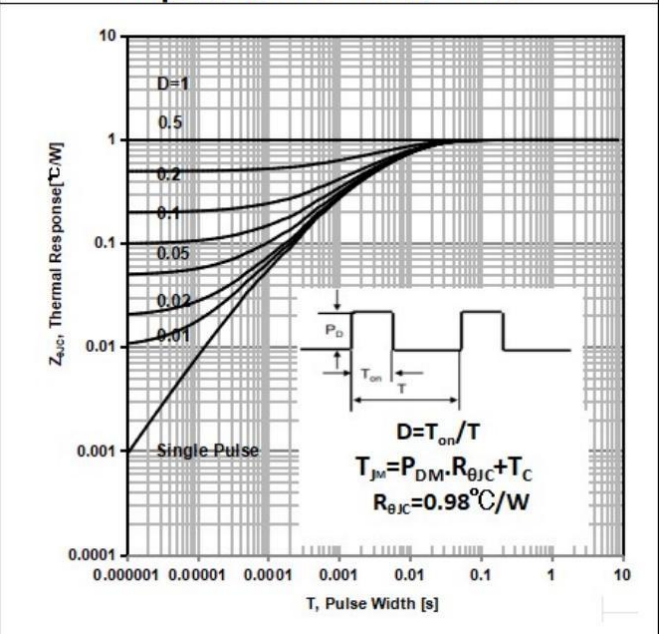
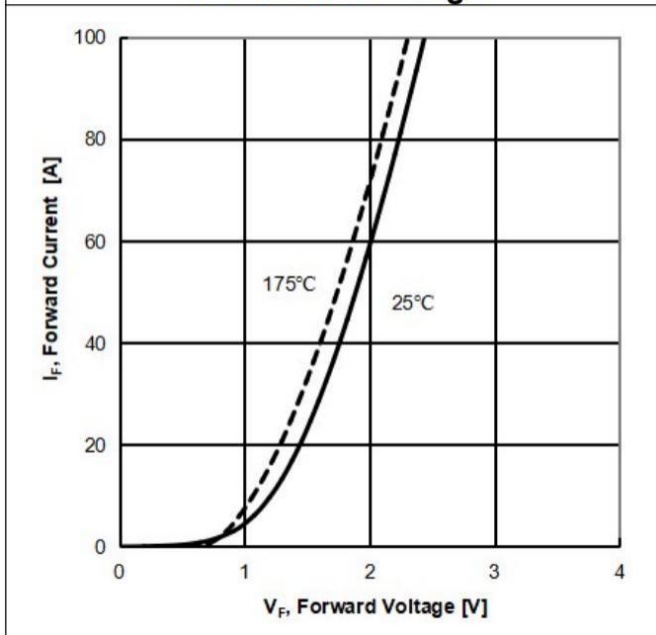
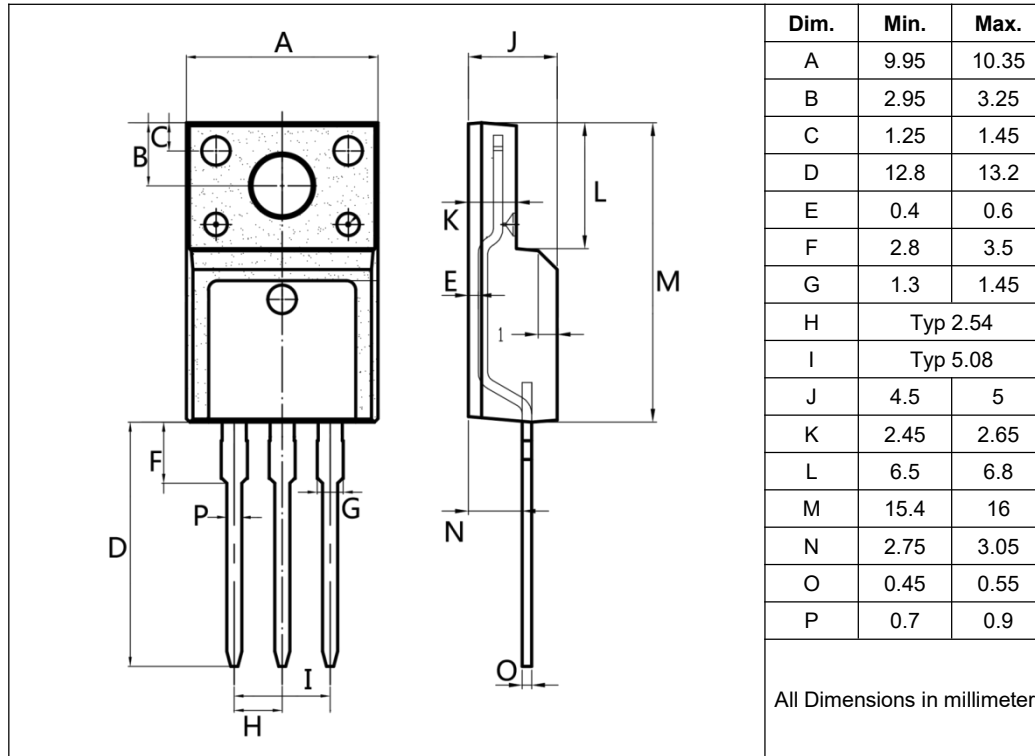


Figure 21: Typical Diode Forward Current vs. Forward Voltage



Package Outlines (Unit: mm)

TO-220F



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